



YOUSHANG SEMICONDUCTOR

**设计研发新型功率器件**

**各类小信号开关**

**中低压及高压大电流等场效应管**

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企业微信二维码



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## Product Summary

Device	$V_{(BR)DSS}$	$R_{DS(on)}$ Max	$I_D$ $T_A = +25^\circ C$
Q1	40V	28m $\Omega$ @ $V_{GS} = 10V$	7.2A
		49m $\Omega$ @ $V_{GS} = 4.5V$	5.4A
Q2	-40V	50m $\Omega$ @ $V_{GS} = -10V$	-5.2A
		79m $\Omega$ @ $V_{GS} = -4.5V$	-4.7A

## Description

This MOSFET has been designed to minimize the on-state resistance and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

## Applications

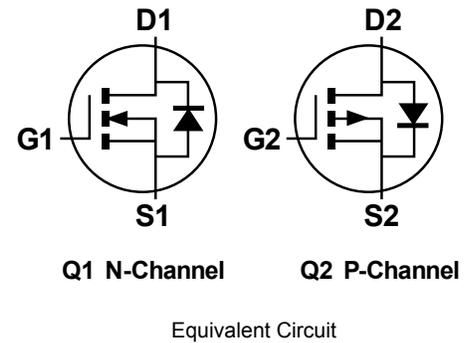
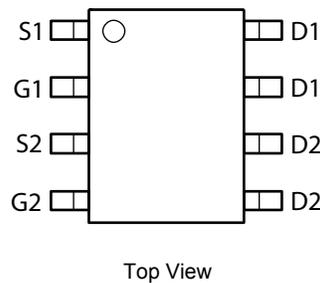
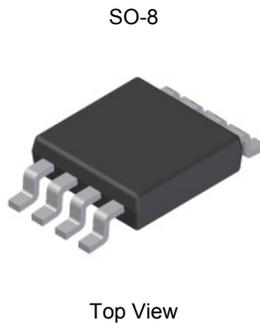
- Motor Control
- Backlighting
- DC-DC Converters
- Power Management Functions

## Features and Benefits

- Low On-Resistance
- Fast Switching Speed

## Mechanical Data

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See diagram below
- Terminals: Finish - Matte Tin annealed over Copper lead frame. Solderable per MIL-STD-202, Method 208  $\text{e3}$
- Weight: 0.074 grams (approximate)



**Maximum Ratings** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

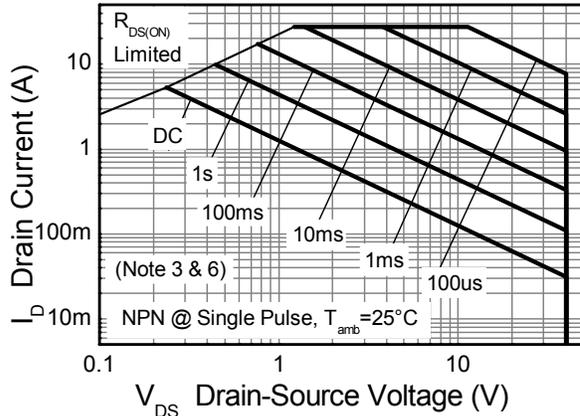
Characteristic		Symbol	N-Channel - Q1	P-Channel - Q2	Units	
Drain-Source Voltage		$V_{DSS}$	40	-40	V	
Gate-Source Voltage		$V_{GSS}$	$\pm 20$	$\pm 20$	V	
Continuous Drain Current	$V_{GS} = 10\text{V}$	$I_D$	(Notes 7 & 9)	7.2	5.2	A
			$T_A = 70^\circ\text{C}$ (Notes 7 & 9)	5.5	4.2	
			(Notes 6 & 9)	5.4	4	
			(Notes 6 & 10)	6.5	4.8	
Pulsed Drain Current	$V_{GS} = 10\text{V}$	$I_{DM}$	27.3	20.4	A	
Continuous Source Current (Body diode)		$I_S$	3.35	3.15	A	
Pulsed Source Current (Body diode)		$I_{SM}$	27.3	20.4	A	

**Thermal Characteristics** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

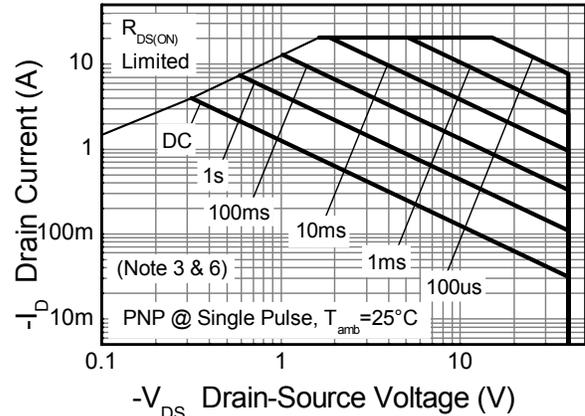
Characteristic		Symbol	N-Channel - Q1	P-Channel - Q2	Unit
Power Dissipation Linear Derating Factor	(Notes 6 & 9)	$P_D$	1.25 10		W mW/ $^\circ\text{C}$
	(Notes 6 & 10)		1.8 14.3		
	(Notes 7 & 9)		2.16 17.2		
	(Notes 6 & 9)		$R_{\theta JA}$	100	
(Notes 6 & 10)	70				
(Notes 7 & 9)	58				
Thermal Resistance, Junction to Ambient	(Notes 9 & 11)	$R_{\theta JL}$	53	53	$^\circ\text{C}/\text{W}$
Operating and Storage Temperature Range		$T_J, T_{STG}$	-55 to +150		$^\circ\text{C}$

- Notes:
5. AEC-Q101  $V_{GS}$  maximum is  $\pm 16\text{V}$ .
  6. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
  7. Same as note (5), except the device is measured at  $t \leq 10$  sec.
  8. Same as note (5), except the device is pulsed with  $D = 0.02$  and pulse width 300  $\mu\text{s}$ . The pulse current is limited by the maximum junction temperature.
  9. For a dual device with one active die.
  10. For a device with two active die running at equal power.
  11. Thermal resistance from junction to solder-point (at the end of the drain lead).

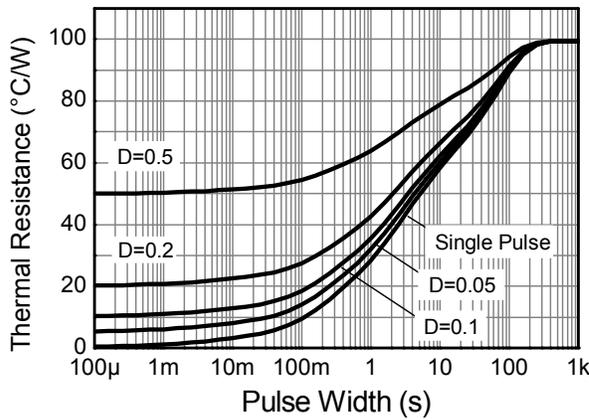
**Thermal Characteristics**



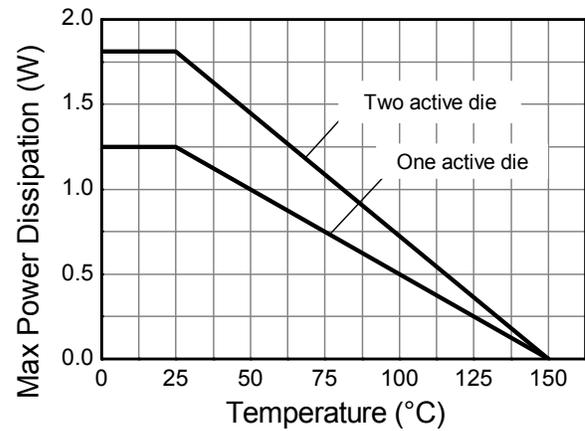
**N-channel Safe Operating Area**



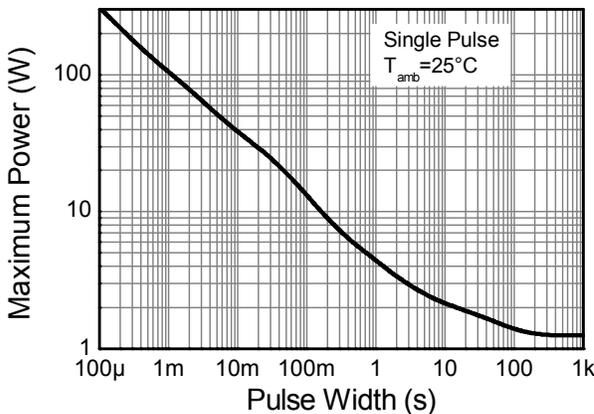
**P-channel Safe Operating Area**



**Transient Thermal Impedance**



**Derating Curve**



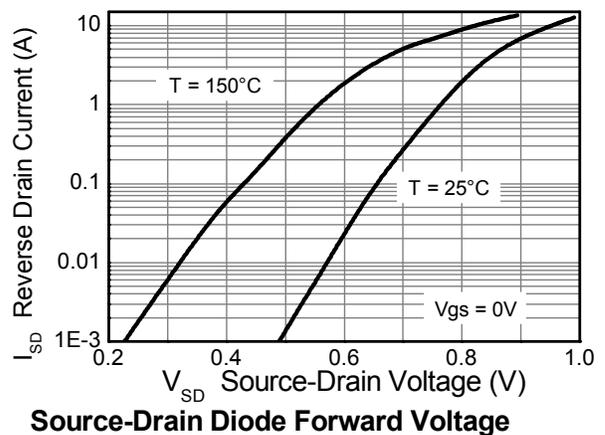
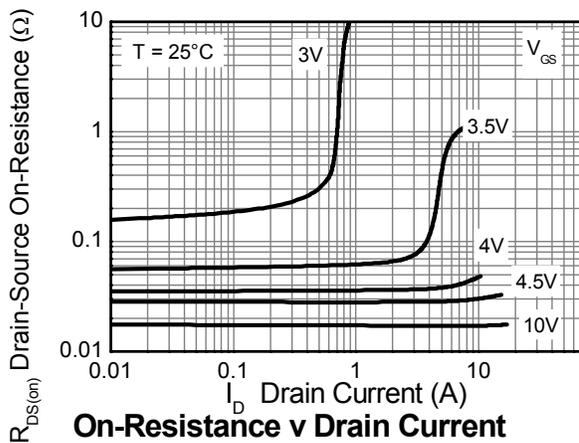
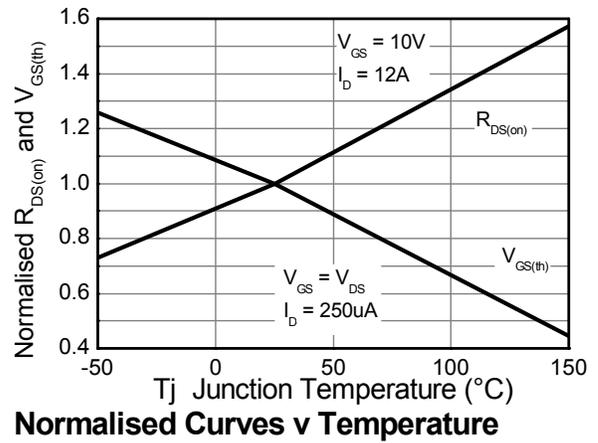
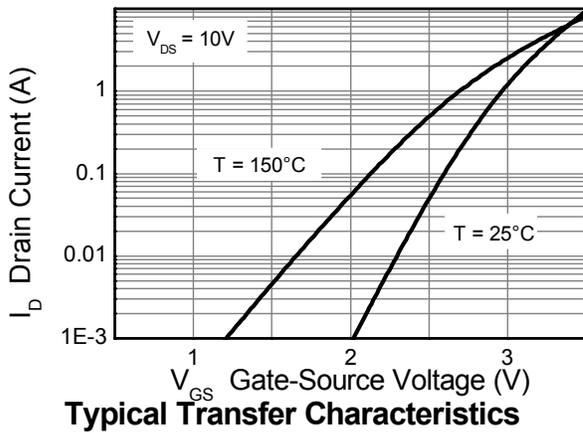
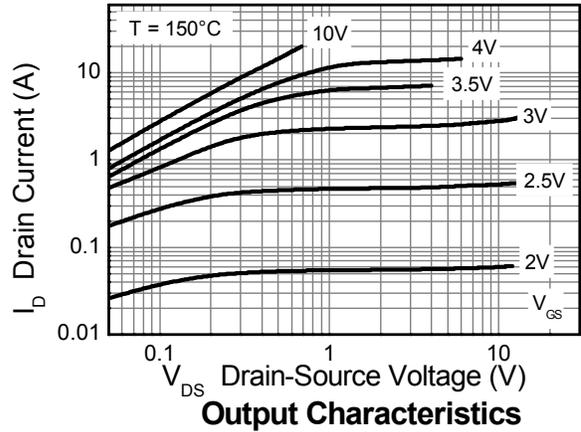
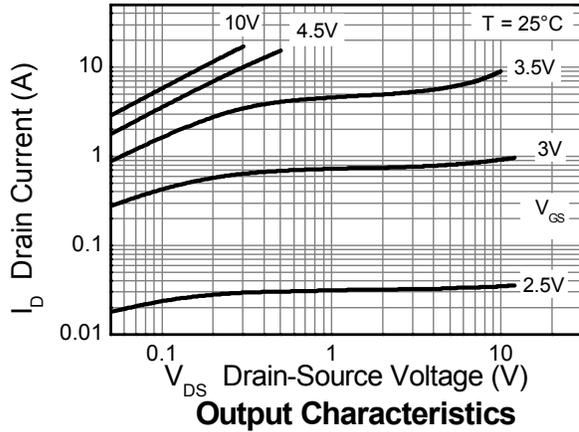
**Pulse Power Dissipation**

**Electrical Characteristics – Q1 N-Channel** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

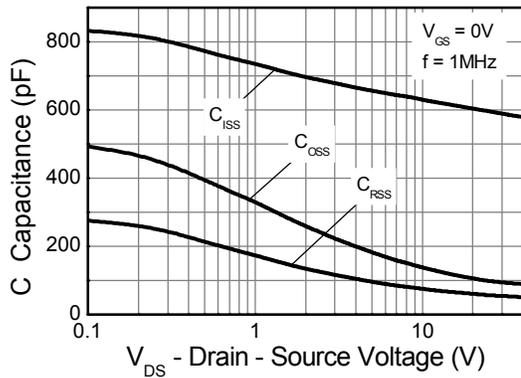
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	40	—	—	V	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	—	—	0.5	μA	V <sub>DS</sub> = 40V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	—	—	±100	nA	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	1.0	—	3.0	V	I <sub>D</sub> = 250μA, V <sub>DS</sub> = V <sub>GS</sub>
Static Drain-Source On-Resistance (Note 12)	R <sub>DS(on)</sub>	—	0.018	0.028	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 6A
			0.033	0.049		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 5A
Forward Transconductance (Notes 12 & 13)	g <sub>fs</sub>	—	22.8	—	S	V <sub>DS</sub> = 15V, I <sub>D</sub> = 6A
Diode Forward Voltage (Note 12)	V <sub>SD</sub>	—	0.845	1.1	V	I <sub>S</sub> = 6A, V <sub>GS</sub> = 0V
Reverse recovery time (Note 13)	t <sub>rr</sub>	—	135	—	ns	I <sub>S</sub> = 6A, di/dt = 100A/μs
Reverse recovery charge (Note 13)	Q <sub>rr</sub>	—	799	—	nC	
<b>DYNAMIC CHARACTERISTICS (Note 13)</b>						
Input Capacitance	C <sub>iSS</sub>	—	604	—	pF	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V f = 1MHz
Output Capacitance	C <sub>oss</sub>	—	106	—	pF	
Reverse Transfer Capacitance	C <sub>rSS</sub>	—	59.6	—	pF	
Total Gate Charge (Note 14)	Q <sub>g</sub>	—	6.5	—	nC	V <sub>GS</sub> = 4.5V
Total Gate Charge (Note 14)	Q <sub>g</sub>	—	12.9	—	nC	V <sub>GS</sub> = 10V
Gate-Source Charge (Note 14)	Q <sub>gs</sub>	—	2.3	—	nC	
Gate-Drain Charge (Note 14)	Q <sub>gd</sub>	—	3.6	—	nC	
Turn-On Delay Time (Note 14)	t <sub>D(on)</sub>	—	4.2	—	ns	V <sub>DD</sub> = 20V, V <sub>GS</sub> = 10V I <sub>D</sub> = 6A, R <sub>G</sub> ≅ 6.0Ω
Turn-On Rise Time (Note 14)	t <sub>r</sub>	—	12.4	—	ns	
Turn-Off Delay Time (Note 14)	t <sub>D(off)</sub>	—	13.8	—	ns	
Turn-Off Fall Time (Note 14)	t <sub>f</sub>	—	10.7	—	ns	

- Notes:
- 12. Measured under pulsed conditions. Pulse width ≤ 300μs; duty cycle ≤ 2%
  - 13. For design aid only, not subject to production testing.
  - 14. Switching characteristics are independent of operating junction temperatures.

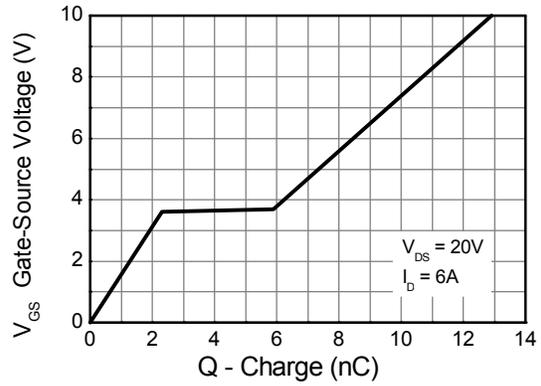
Typical Characteristics – Q1 N-Channel



**Typical Characteristics – Q1 N-Channel - (cont.)**

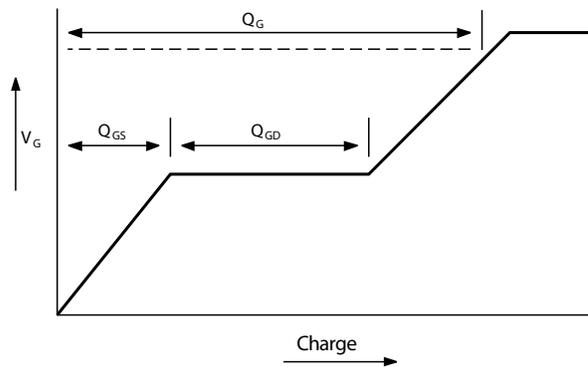


**Capacitance v Drain-Source Voltage**

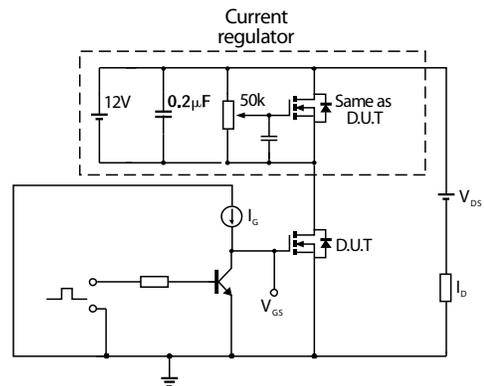


**Gate-Source Voltage v Gate Charge**

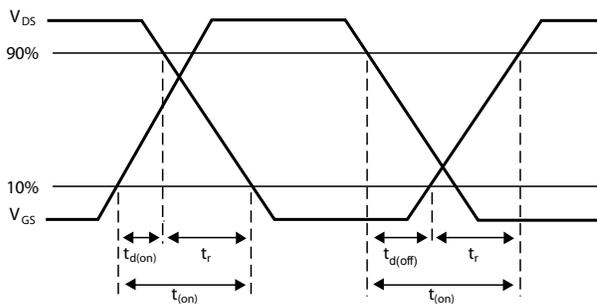
**Test Circuits – Q1 N-Channel**



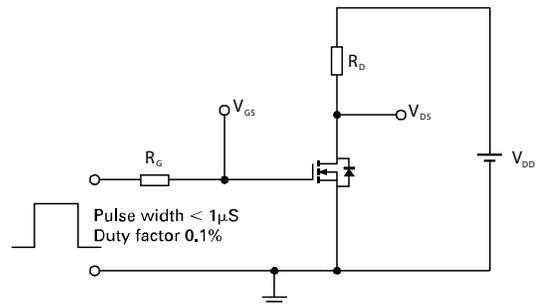
**Basic gate charge waveform**



**Gate charge test circuit**



**Switching time waveforms**



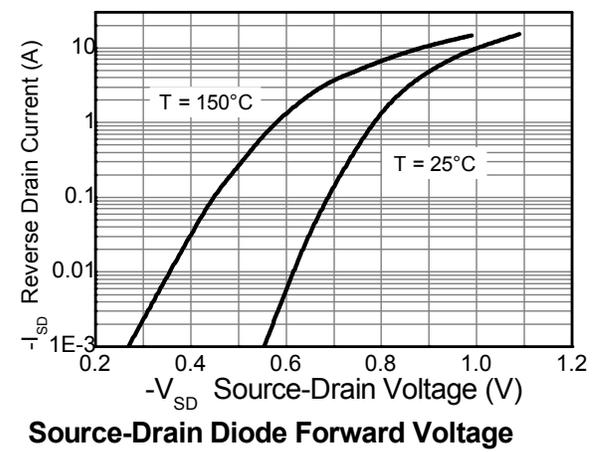
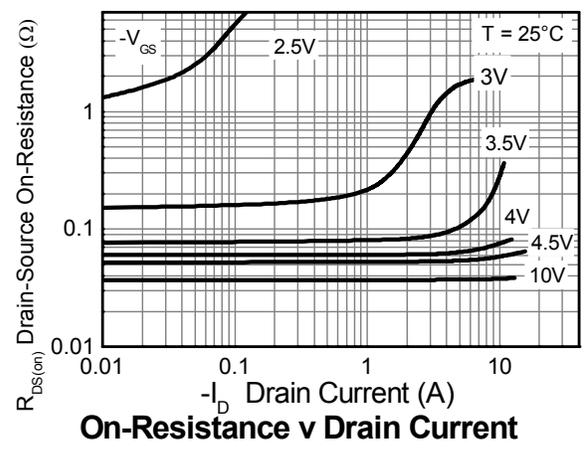
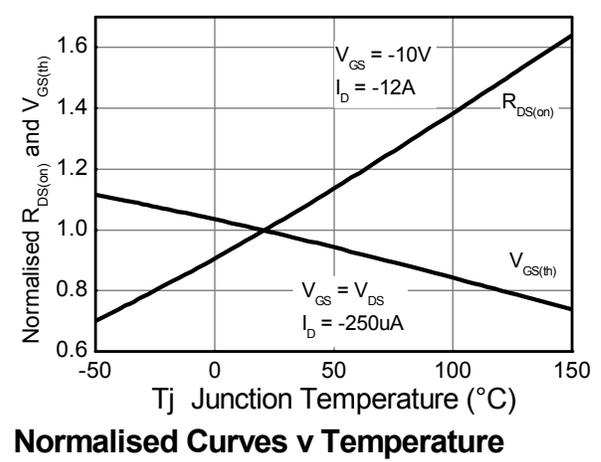
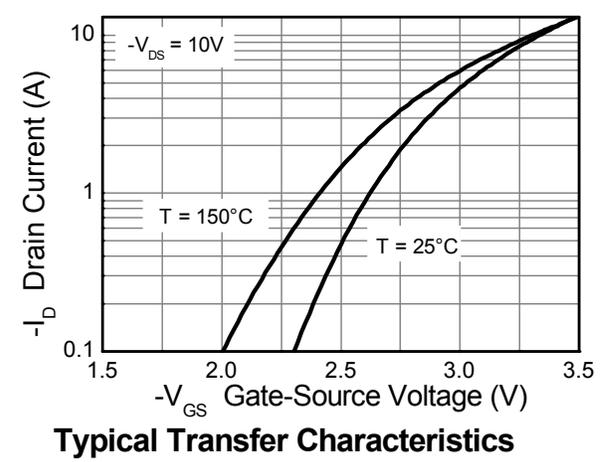
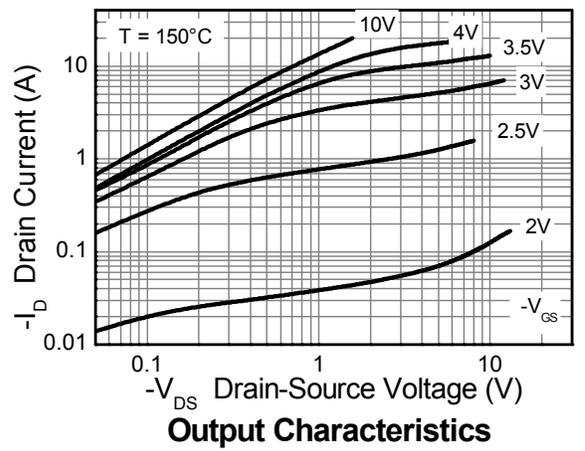
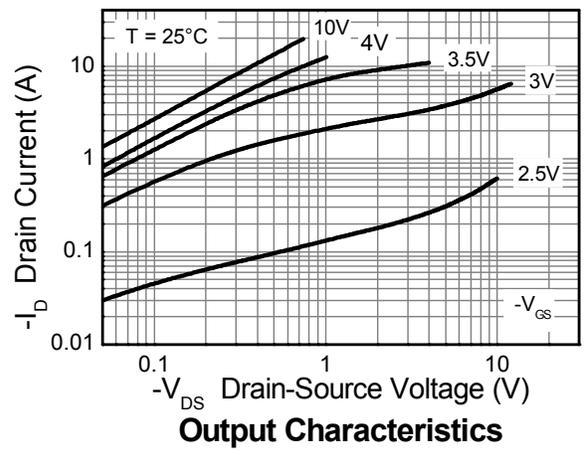
**Switching time test circuit**

**Electrical Characteristics – Q2 P-Channel** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

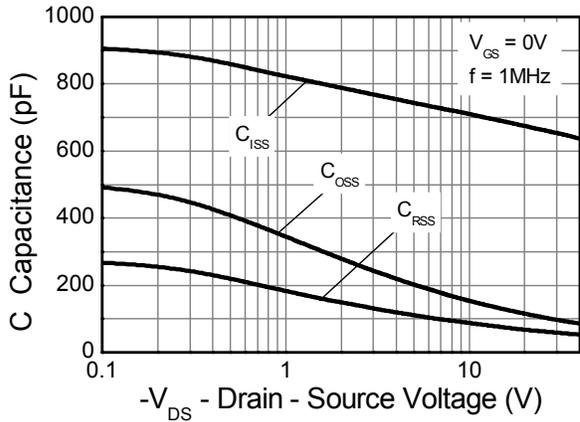
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	-40	—	—	V	$I_D = -250 \mu\text{A}$ , $V_{GS} = 0\text{V}$
Zero Gate Voltage Drain Current	$I_{DSS}$	—	—	-0.5	$\mu\text{A}$	$V_{DS} = -40\text{V}$ , $V_{GS} = 0\text{V}$
Gate-Source Leakage	$I_{GSS}$	—	—	$\pm 100$	nA	$V_{GS} = \pm 20\text{V}$ , $V_{DS} = 0\text{V}$
<b>ON CHARACTERISTICS</b>						
Gate Threshold Voltage	$V_{GS(th)}$	-1.0	—	-3.0	V	$I_D = -250 \mu\text{A}$ , $V_{DS} = V_{GS}$
Static Drain-Source On-Resistance (Note 12)	$R_{DS(on)}$	—	0.039	0.050	$\Omega$	$V_{GS} = -10\text{V}$ , $I_D = -6\text{A}$
			0.060	0.079		$V_{GS} = -4.5\text{V}$ , $I_D = -5\text{A}$
Forward Transconductance (Notes 12 & 13)	$g_{fs}$	—	16.6	—	S	$V_{DS} = -15\text{V}$ , $I_D = -6\text{A}$
Diode Forward Voltage (Note 13)	$V_{SD}$	—	-0.865	-1.1	V	$I_S = -6\text{A}$ , $V_{GS} = 0\text{V}$
Reverse Recovery Time (Note 13)	$t_{rr}$	—	138	—	ns	$I_S = -6\text{A}$ , $di/dt = 100\text{A}/\mu\text{s}$
Reverse Recovery Charge (Note 13)	$Q_{rr}$	—	841	—	nC	
<b>DYNAMIC CHARACTERISTICS (Note 13)</b>						
Input Capacitance	$C_{iss}$	—	674	—	pF	$V_{DS} = -20\text{V}$ , $V_{GS} = 0\text{V}$ $f = 1\text{MHz}$
Output Capacitance	$C_{oss}$	—	115	—	pF	
Reverse Transfer Capacitance	$C_{rss}$	—	67.7	—	pF	
Total Gate Charge (Note 14)	$Q_g$	—	7.0	—	nC	$V_{GS} = -4.5\text{V}$
Total Gate Charge (Note 14)	$Q_g$	—	14	—	nC	$V_{GS} = -10\text{V}$
Gate-Source Charge (Note 14)	$Q_{gs}$	—	2.2	—	nC	
Gate-Drain Charge (Note 14)	$Q_{gd}$	—	3.7	—	nC	
Turn-On Delay Time (Note 14)	$t_{D(on)}$	—	2.3	—	ns	$V_{DD} = -20\text{V}$ , $V_{GS} = -10\text{V}$ $I_D = -6\text{A}$ , $R_G \cong 6.0\Omega$
Turn-On Rise Time (Note 14)	$t_r$	—	14.1	—	ns	
Turn-Off Delay Time (Note 14)	$t_{D(off)}$	—	25.1	—	ns	
Turn-Off Fall Time (Note 14)	$t_f$	—	14.3	—	ns	

- Notes:
12. Measured under pulsed conditions. Pulse width  $\leq 300\mu\text{s}$ ; duty cycle  $\leq 2\%$
  13. For design aid only, not subject to production testing.
  14. Switching characteristics are independent of operating junction temperatures.

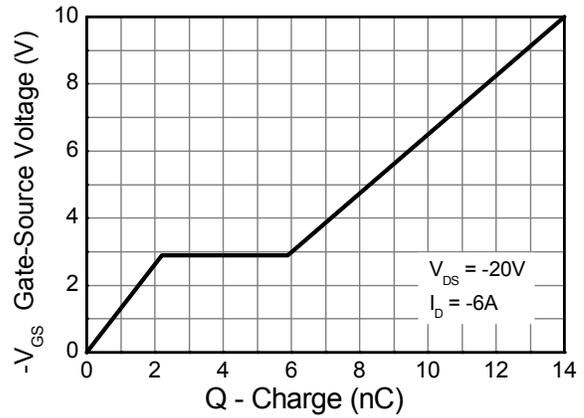
**Typical Characteristics – Q2 P-Channel**



**Typical Characteristics – Q2 P-Channel – (cont.)**

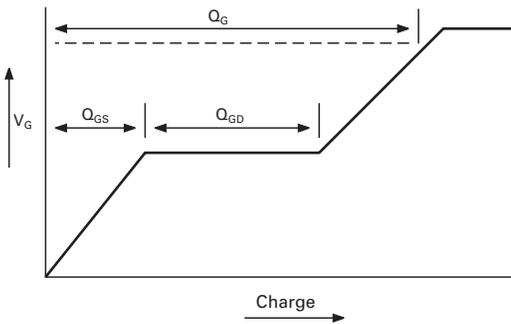


**Capacitance v Drain-Source Voltage**

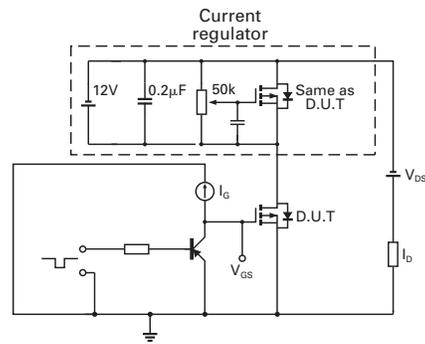


**Gate-Source Voltage v Gate Charge**

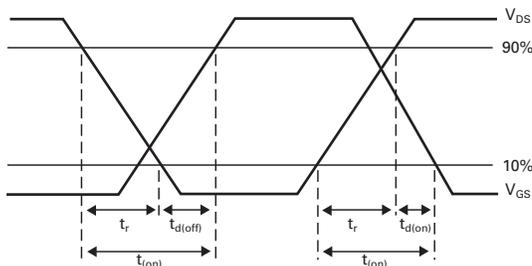
**Test Circuits – Q2 P-Channel**



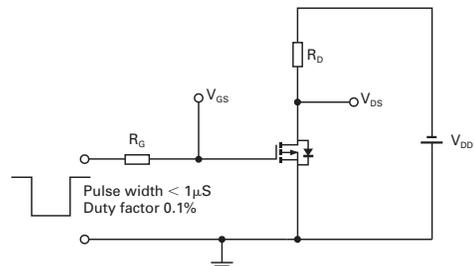
**Basic gate charge waveform**



**Gate charge test circuit**

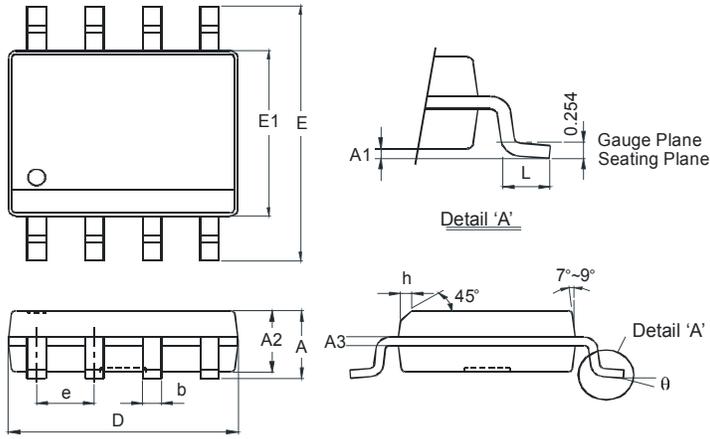


**Switching time waveforms**



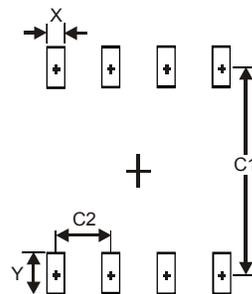
**Switching time test circuit**

### Package Outline Dimensions



SO-8		
Dim	Min	Max
A	-	1.75
A1	0.10	0.20
A2	1.30	1.50
A3	0.15	0.25
b	0.3	0.5
D	4.85	4.95
E	5.90	6.10
E1	3.85	3.95
e	1.27 Typ	
h	-	0.35
L	0.62	0.82
θ	0°	8°
All Dimensions in mm		

### Suggested Pad Layout



Dimensions	Value (in mm)
X	0.60
Y	1.55
C1	5.4
C2	1.27